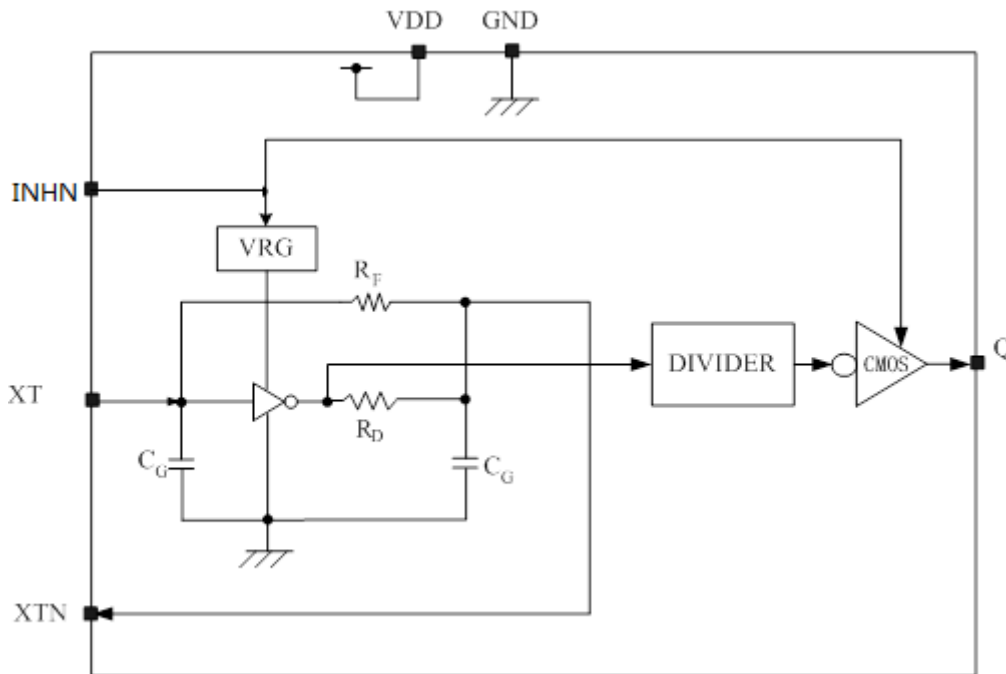






### Block Diagram



### Function Description

#### Power-saving Pull-up Resistor

The INHN pin pull-up resistance RUP1 or RUP2 changes in response to the input level(HIGH or LOW). When INHN is tied LOW level, the pull-up resistance is large(RUP1),reducing the current consumed by the resistance. When INHN is left open circuit, the pull-up resistance is small(RUP2),which increases the input susceptibility to external noise. However, the pull-up resistance ties the INHN pin HIGH level to prevent external noise from unexpectedly stopping the output.

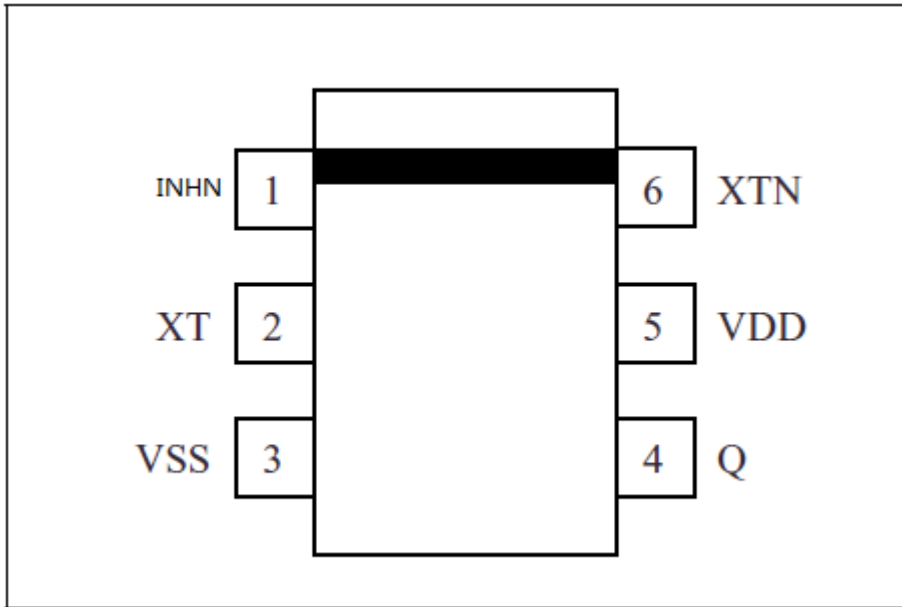
#### Oscillation Detector Function

The XO5024ALx series also feature an oscillation detector circuit. This circuit functions make the outputs disable until the oscillator circuit starts and oscillation becomes stable. This alleviates the danger of abnormal oscillator output at oscillator start-up when power is applied or when INHN is switched



XO5024ALx series  
Fundamental Crystal Oscillator IC

**Pin Assignment**



**Pad Description**

Sym.	Pin No	Type	Description	
XTN	6	O	Amplifier output.	Crystal connected between XT and XTN
XT	2	I	Amplifier input.	
V <sub>DD</sub>	5	P	Supply voltage	
V <sub>SS</sub>	3	P	Ground	
Q	4	O	Output. Output frequency determined by internal circuit to one of f <sub>0</sub> , f <sub>0</sub> /2, f <sub>0</sub> /4, f <sub>0</sub> /8, f <sub>0</sub> /16,	
INH <sub>N</sub>	1	I	Output state control input. High impedance when LOW. Power-saving pull-up resistor built in.	



XO5024ALx series  
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**Maximum Ratings**

Storage Temperature .....	-65°C to +150°C
Supply Voltage to Ground Potential (V <sub>DD</sub> to GND) .....	-0.5V to +7.0V
DC Input (All Other Inputs except V <sub>DD</sub> & GND) ...	-0.5V to V <sub>DD</sub> +0.5V
DC Output .....	-0.5V to V <sub>DD</sub> +0.5V
DC Output Current (all outputs) .....	20mA

**Note:**

Stresses greater than those listed under MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

**Recommended Operating Conditions**

(GND=0V, unless otherwise noted.)

Sym.	Parameter	Series	Conditions	Min	Typ	Max	Unit
V <sub>DD</sub>	Supply voltage	All series	C <sub>L</sub> = 15pF	2.5	-	5.5	V
V <sub>IN</sub>	Input voltage	All series	-	GND	-	VDD	V
T <sub>A</sub>	Operating temperature	All series	-	-40	-	+85	°C
f <sub>0</sub>	Oscillation frequency*1	5024x1-5024x6	Vdd=2.5V~5.5V -	10	-	50	MHz
f <sub>OUT</sub>	Output frequency	5024x1-5024x6	Vdd=2.5V~5.5V	1	-	50	MHz

**Reliability Data**

Sym.	Parameter	Series	Conditions	Min	Typ	Max	Unit
ESD	Human Body Model	All series	MIL-STD-883H Method 3015.8	+/-3000	+/-6500		V
					-		

Note: Industrial Standard ESD: HBM Model +/-2000V



XO5024ALx series  
Fundamental Crystal Oscillator IC

**DC Electrical Characteristics**

XO5024x1 to XO5024x6 ( $V_{DD} = 2.5$  to  $5.5V$ ,  $T_A = -40$  to  $85\text{ }^\circ\text{C}$ , unless otherwise noted.)

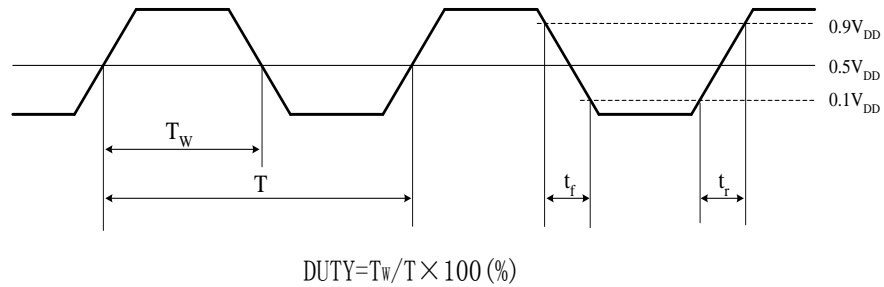
Sym.	Parameter	Condition	Rating			Unit	
			min	typ	max		
$V_{OH}$	HIGH-level output voltage	Q: Measurement cct3, $I_{OH}=4mA$	$V_{DD}-0.4$	-	-	V	
$V_{OL}$	LOW-level output voltage	Q: Measurement cct3, $I_{OL}=4mA$	-	-	0.4	V	
$V_{IH}$	HIGH-level input voltage	INH, Measurement cct4	$0.7V_{DD}$	-	-	V	
$V_{IL}$	LOW-level input voltage	INH, Measurement cct4	-	-	$0.3V_{DD}$	V	
$I_Z$	Output leakage current	Q: Measurement cct5, INH=LOW	$V_{OH}=V_{DD}$	-	-	10	$\mu A$
			$V_{OL}=GND$	-	-	10	$\mu A$
$I_{DD}$	Current consumption	Measurement cct 1, XO5024AL1( $f_0$ ),no load INH=open, $f_0=48MHz$ $f_{OUT}=48MHz$	$V_{DD}=3.3V$	-	1.6	2.4	mA
			$V_{DD}=2.5V$	-	1.3	2.0	mA
			$V_{DD}=1.8V$	-	1.0	1.5	mA
		Measurement cct 1, XO5024AL2( $f_0/2$ ),no load INH=open, $f_0=48MHz$ $f_{OUT}=24MHz$	$V_{DD}=3.3V$	-	1.5	2.3	mA
			$V_{DD}=2.5V$	-	1.2	1.8	mA
			$V_{DD}=1.8V$	-	0.9	1.4	mA
		Measurement cct 1, XO5024AL3( $f_0/4$ ),no load INH=open, $f_0=48MHz$ $f_{OUT}=12MHz$	$V_{DD}=3.3V$	-	1.3	2.0	mA
			$V_{DD}=2.5V$	-	1.0	1.5	mA
			$V_{DD}=1.8V$	-	0.8	1.2	mA
		Measurement cct 1, XO5024AL4( $f_0/8$ ),no load INH=open, $f_0=48MHz$ $f_{OUT}=6MHz$	$V_{DD}=3.3V$	-	1.1	1.7	mA
			$V_{DD}=2.5V$	-	0.9	1.4	mA
			$V_{DD}=1.8V$	-	0.75	1.15	mA
Measurement cct 1, XO5024AL5( $f_0/16$ ),no load INH=open, $f_0=48MHz$ $f_{OUT}=3MHz$	$V_{DD}=3.3V$	-	1.05	1.6	mA		
	$V_{DD}=2.5V$	-	0.85	1.3	mA		
	$V_{DD}=1.8V$	-	0.7	1.1	mA		
$R_f$	Oscillator feedback resistance	-	50	100	200	K $\Omega$	
$C_G$	Oscillator capacitance	Design value(a monitor pattern on a wafer is tested),Excluding parasitic capacitance	4.8	6	7.2	pF	
$C_D$			8	10	12	pF	



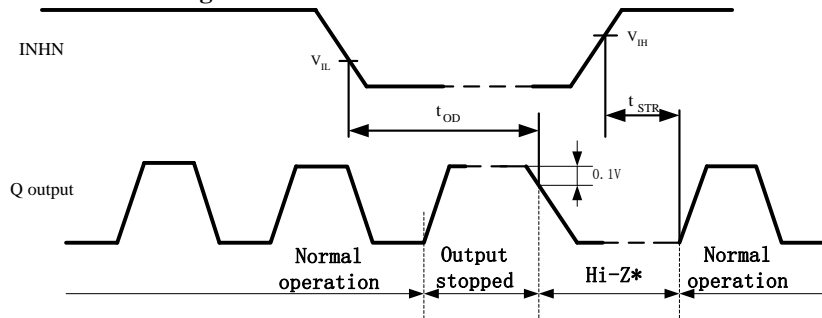
XO5024ALx series  
Fundamental Crystal Oscillator IC

AC Electrical Characteristics

Output switching waveform



Output disable and oscillation start timing chart



When INHN goes HIGH to LOW, the Q output goes HIGH once and then becomes high impedance.

When INHN goes LOW to HIGH, the Q output from high impedance to normal output operation when the oscillation starts (oscillation is detected)

\*: the high-impedance interval in the figure is shown as a LOW level due to the 1KΩ pull-down resistor connected to the Q pin (see “Measurement circuit 2” in the “Measurement circuits” section)

XO5024 Series ( $V_{DD}=1.40$  to  $5.5$ ,  $T_a=-40$  to  $85^\circ\text{C}$  unless otherwise noted)

Parameter	Symbol	Condition	Min	Type	Max	Unit	
Output rise time	$t_{r1}$	Measurement cct1, $CL=15\text{Pf}$ , $0.1V_{DD}$ to $0.9V_{DD}$	$V_{DD}=2.25$ to $3.36\text{ V}$	-	2.0	4.5	ns
	$t_{r2}$		$V_{DD}=1.60$ to $2.25\text{V}$	-	3.0	5.0	ns
Output fall time	$t_{f1}$	Measurement cct1, $CL=15\text{Pf}$ , $0.1V_{DD}$ to $0.9V_{DD}$	$V_{DD}=2.25$ to $3.36\text{ V}$	-	2.0	4.5	ns
	$t_{f2}$		$V_{DD}=1.60$ to $2.25\text{ V}$	-	3.0	5.0	ns
Output rise time	$t_{r1}$	Measurement cct1, $CL=50\text{Pf}$ , $0.1V_{DD}$ to $0.9V_{DD}$	$V_{DD}=2.25$ to $3.36\text{ V}$	-	4.8	9.6	ns
	$t_{r2}$		$V_{DD}=4.5$ to $5.5\text{V}$	-	3.8	7.6	ns
Output fall time	$t_{f1}$	Measurement cct1, $CL=50\text{Pf}$ , $0.1V_{DD}$ to $0.9V_{DD}$	$V_{DD}=2.25$ to $3.36\text{ V}$	-	4.8	9.6	ns
	$t_{f2}$		$V_{DD}=4.5$ to $5.5\text{ V}$	-	3.8	7.6	ns
Output duty cycle	Duty	Measurement cct 1, $T_A=25^\circ\text{C}$ , $C_L=15\text{pF}$	45	50	55	%	

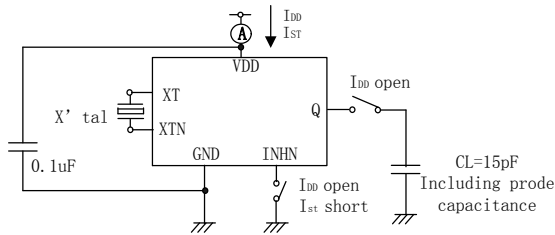


XO5024ALx series  
Fundamental Crystal Oscillator IC

Measurement Circuit

Measurement cct1

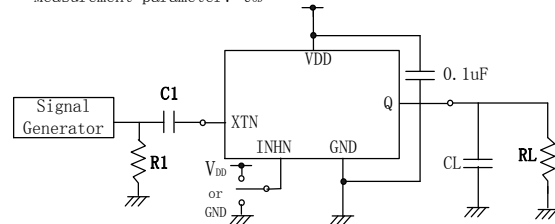
Measurement parameter:  $I_{DD}$ ,  $I_{st}$ , Duty,  $t_r$ ,  $t_f$



Note: The AC characteristics are observed using an oscilloscope on pin Q

Measurement cct2

Measurement parameter:  $t_{\omega}$

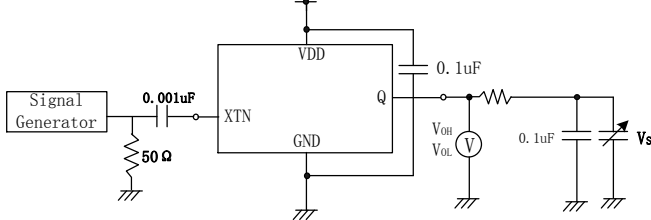


XTN input signal: 1Vp-p, sina wave

C1: 0.001uF CL: 15pF  
R1: 50Ω RL: 1KΩ

Measurement cct3

Measurement parameter:  $V_{OH}$ ,  $V_{OL}$



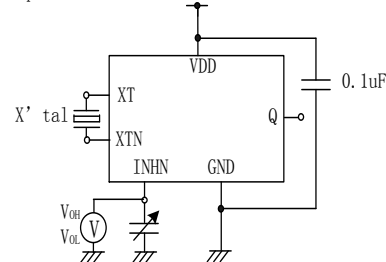
$V_S$  adjusted such that  $\Delta V=50 \times I_{OH}$

$V_S$  adjusted such that  $\Delta V=50 \times I_{OL}$

XTN input signal: 1Vp-p, sina wave

Measurement cct4

Measurement parameter:  $V_{IH}$ ,  $V_{IL}$



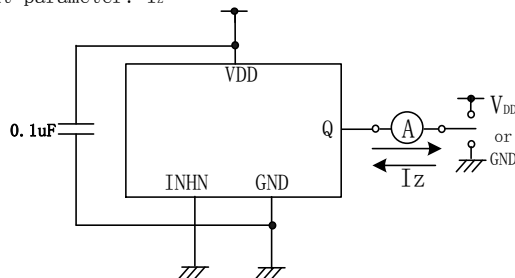
$V_{IH}$ : Voltage is 0V to  $V_{DD}$  transition that changes the output state.

$V_{IL}$ : Voltage is  $V_{DD}$  to 0V transition that changes the output state.

INHN has an oscillation stop function

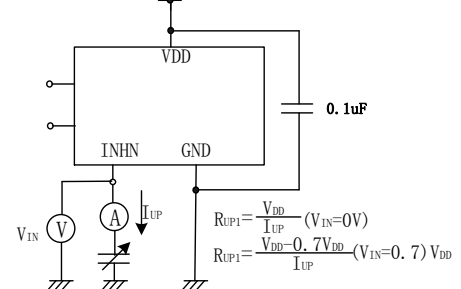
Measurement cct5

Measurement parameter:  $I_z$



Measurement cct6

Measurement parameter:  $R_{UP1}$ ,  $R_{UP2}$



$$R_{UP1} = \frac{V_{DD}}{I_{UP}} \quad (V_{IN}=0V)$$

$$R_{UP1} = \frac{V_{DD}-0.7V_{DD}}{I_{UP}} \quad (V_{IN}=0.7)V_{DD}$$



Package Information

(Unit: mm)

